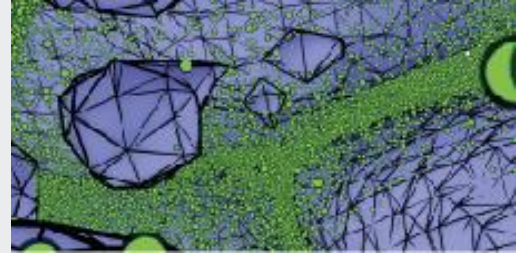


# 1<sup>st</sup> Erlangen Atom Probe Tomography School

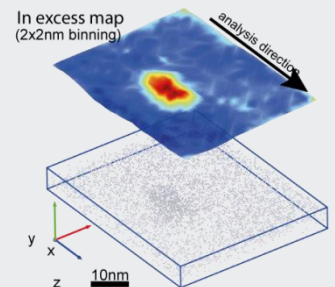
## September 12 - 15, 2016

This 4 day intensive course will provide an introduction to high field physics, atom probe instrumentation, sample preparation and data interpretation to the novice and intermediate level atom prober. As an outcome, the participants will be able to independently perform atom probe experiments, reconstruct their data and carry out in-depth analysis of a variety of different problem sets. A full day FIB - lift-out tutorial is included.



### Lectures:

- Introduction to atom probe tomography
- Atom probe instrumentation
- Atom probe sample preparation
- Atom probe maintenance Q&A (Cameca)
- Reconstruction and analysis of APT data (+ practical)
- Electropolishing of APT samples (+ practical)
- FIB preparation of APT samples (full day practical in three groups on FEI Helios 600i/660, Zeiss XB 540)
- Operating the atom probe (practical, LEAP 4000X HR)



### Organizing committee:

Peter Felfer, peter.felfer@fau.de, Aruna Prakash, arun.prakash@fau.de

### Invited guest lecturer:

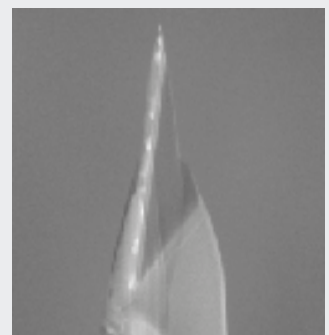
Dr. Baptiste Gault, MPI for Iron Research, Düsseldorf

**Registration:** eam-apschool@fau.de

**Deadline:** July 1, 2016

The attendance is limited to 25 participants (10 reserved for FAU)

Registration fee: € 250, coffee breaks, lunches and social event included (for FAU members, this is covered by the EAM)



### Venue:

Institute I, Materials Science and Engineering  
Friedrich-Alexander-Universität Erlangen-Nürnberg  
Martensstraße 5, 3.OG, 91058 Erlangen